

What is claimed is:

1. An electrical inspection method comprising:
electrically connecting a signal line to a first power source line to supply a power
5 source voltage to said signal line;
supplying said power source voltage to a pixel to accumulate a predetermined
electric charge in a holding capacitor;
separating said signal line from said first power source line electrically after
accumulating said predetermined electric charge in said holding capacitor;
10 connecting said signal line to a second power source line electrically after
separating said signal line from said first power source line electrically;
reading out said electric charge that is accumulated via said signal line and said
second power source line; and
inspecting said pixel relying upon the electric charge that is read out.
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2. An electrical inspection method according to claim 1, wherein the connection of
said first power source line to said signal line and the connection of said second power
source line to said signal line, are controlled by an inverter.
- 20 3. An electrical inspection method comprising:
connecting a signal line to a first power source line electrically to supply a first
power source voltage to said signal line;
supplying said first power source voltage to a pixel to accumulate a predetermined
electric charge in a holding capacitor;
25 separating said signal line from said first power source line electrically after
accumulating said predetermined electric charge in said holding capacitor;
connecting said signal line to a second power source line electrically after
separating said signal line from said first power source line electrically;
supplying a second power source voltage to said signal line and to said second
30 power source line;

reading out said electric charge that is accumulated via said signal line and said second power source line; and

inspecting said pixel relying upon the electric charge that is read out.

5 4. An electrical inspection method according to claim 3, wherein said first power source voltage and said second power source voltage are different in height from each other.

5. An electrical inspection method according to claim 3, wherein the connection of
10 said first power source line to said signal line and the connection of said second power source line to said signal line, are controlled by an inverter.

6. An electrical inspection method for inspecting an element substrate having a switching element and a holding capacitor in each pixel, comprising:

15 connecting a first power source line served with a first power source voltage to a signal line electrically;

turning on said switching element to connect said signal line to said holding capacitor;

20 turning off said switching element after connecting said signal line to said holding capacitor;

separating said first power source line from said signal line electrically after turning off said switching element;

connecting a second power source line to said signal line electrically after separating said first power source line from said signal line electrically;

25 placing said second power source line in a floating state after supplying a second power source voltage to said second power source line;

turning on said switching element after placing said second power source line in said floating state to read out the electric charge held by said holding capacitor via said signal line and said second power source line; and

30 inspecting said pixel relying upon the amount of the electric charge after reading

out the electric charge.

7. An electrical inspection method according to claim 6, wherein said first power source voltage is supplied to said first power source line via a connection terminal
5 provided over said element substrate.

8. An electrical inspection method according to claim 6, wherein said second power source voltage is supplied to said second power source line via a connection terminal provided over said element substrate.

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9. An electrical inspection method according to claim 6, wherein said first power source voltage and said second power source voltage are different in height from each other.

15 10. An electrical inspection method according to claim 6, wherein the connection of said first power source line to said signal line and the connection of said second power source line to said signal line, are controlled by an inverter.

11. An electrical inspection method for inspecting an element substrate having a
20 switching element and a holding capacitor in the pixels, comprising:

connecting a first power source line served with a first power source voltage to a signal line electrically;

turning on said switching element to connect said signal line to said holding capacitor to thereby accumulate an electric charge in said holding capacitor;

25 turning off said switching element after accumulating the electric charge in said holding capacitor;

separating said first power source line from said signal line after turning off said switching element;

30 connecting a second power source line to said signal line after separating said first power source line from said signal line;

placing said second power source line in a floating state after supplying a second power source voltage to said second power source line; and

turning on said switching element to read out the electric charge held by said holding capacitor via said signal line and said second power source line; and

5 inspecting said pixel relying upon the amount of the electric charge after reading out the electric charge.

12. An electrical inspection method according to claim 11, wherein said first power source voltage is supplied to said first power source line via a connection terminal
10 provided over said element substrate.

13. An electrical inspection method according to claim 11, wherein said second power source voltage is supplied to said second power source line via a connection terminal provided over said element substrate.

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14. An electrical inspection method according to claim 11, wherein said first power source voltage and said second power source voltage are different in height from each other.

20 15. An electrical inspection method according to claim 11, wherein the connection of said first power source line to said signal line and the connection of said second power source line to said signal line, are controlled by an inverter.

16. A method of fabricating a semiconductor display device having a holding
25 capacitor in each pixel, comprising:

connecting a signal line to a first power source line electrically to thereby supply a power source voltage to said signal line;

supplying said power source voltage to said pixel to accumulate a predetermined electric charge in said holding capacitor;

30 separating said signal line from said first power source line electrically after

accumulating the predetermined electric charge in said holding capacitor;

connecting said signal line to a second power source line electrically after separating said signal line from said first power source line;

reading said electric charge that is accumulated via said signal line and said
5 second power source line; and

inspecting said pixel relying upon the electric charge that is read out.

17. A method of fabricating a semiconductor display device according to claim 9,
wherein the connection of said first power source line to said signal line and the connection
10 of said second power source line to said signal line, are controlled by an inverter.

18. A method of fabricating a semiconductor display device having a holding capacitor in each pixel, comprising:

connecting a signal line to a first power source line electrically to thereby supply a
15 first power source voltage to said signal line;

supplying said first power source voltage to said pixel to accumulate a predetermined electric charge in said holding capacitor;

separating said signal line from said first power source line electrically after accumulating a predetermined electric charge in said holding capacitor;

20 connecting said signal line to a second power source line electrically after separating said signal line from said first power source line electrically;

supplying a second power source voltage to said signal line and to said second power source line;

reading out said electric charge that is accumulated via said signal line and said
25 second power source line; and

inspecting said pixel relying upon the electric charge that is read out.

19. A method of fabricating a semiconductor display device according to claim 18,
wherein said first power source voltage and said second power source voltage are different
30 in height from each other.

20. A method of fabricating a semiconductor display device according to claim 18, wherein the connection of said first power source line to said signal line and the connection of said second power source line to said signal line, are controlled by an inverter.

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21. A method of fabricating a semiconductor display device having a switching element and a holding capacitor in each pixel, comprising:

connecting a first power source line served with a first power source voltage to a signal line electrically;

10 turning said switching element on to connect said signal line to said holding capacitor;

turning said switching element off after connecting said signal line to said holding capacitor;

15 separating said first power source line from said signal line electrically after turning said switching element off;

connecting a second power source line to said signal line electrically after separating said first power source line from said signal line electrically;

placing said second power source line in a floating state after supplying a second power source voltage to said second power source line; and

20 turning said switching element on after placing said second power source line in the floating state to read out the electric charge held by said holding capacitor via said signal line and said second power source line; and

inspecting said pixel relying upon the amount of the electric charge after reading out the electric charge.

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22. A method of fabricating a semiconductor display device according to claim 21, wherein said first power source voltage is supplied to said first power source line via a connection terminal provided over said element substrate.

30 23. A method of fabricating a semiconductor display device according to claim 21,

wherein said second power source voltage is supplied to said second power source line via a connection terminal provided over said element substrate.

24. A method of fabricating a semiconductor display device according to claim 21,
5 wherein said first power source voltage and said second power source voltage are different in height from each other.

25. A method of fabricating a semiconductor display device according to claim 21,
wherein the connection of said first power source line to said signal line and the connection
10 of said second power source line to said signal line, are controlled by an inverter.

26. A method of fabricating a semiconductor display device having a switching element and a holding capacitor in the pixels, comprising:

- connecting a first power source line served with a first power source voltage to a
15 signal line electrically;
- turning said switching element on to connect said signal line to said holding capacitor to thereby accumulate an electric charge in said holding capacitor;
- turning said switching element off after accumulating an electric charge in said holding capacitor;
- 20 separating said first power source line from said signal line electrically after turning said switching element off;
- connecting a second power source line to said signal line electrically;
- placing said second power source line in a floating state after supplying a second power source voltage to said second power source line;
- 25 turning said switching element on to read out the electric charge held by said holding capacitor via said signal line and said second power source line, and
- inspecting said pixel relying upon the amount of the electric charge after reading out the electric charge.

30 27. A method of fabricating a semiconductor display device according to claim 26,

wherein said first power source voltage is supplied to said first power source line via a connection terminal provided over said element substrate.

28. A method of fabricating a semiconductor display device according to claim 26,
5 wherein said second power source voltage is supplied to said second power source line via a connection terminal provided over said element substrate.

29. A method of fabricating a semiconductor display device according to claim 26,
10 wherein said first power source voltage and said second power source voltage are different in height from each other.

30. A method of fabricating a semiconductor display device according to claim 26,
wherein the connection of said first power source line to said signal line and the connection
of said second power source line to said signal line, are controlled by an inverter.

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